

20-40GHz Medium Power Amplifier

GaAs Monolithic Microwave IC

Description

The CHA3093 is a high gain broadband four-stage monolithic medium power amplifier. It is designed for a wide range of applications, from military to commercial communication systems. The backside of the chip is both RF and DC grounds. This helps simplify the assembly process.

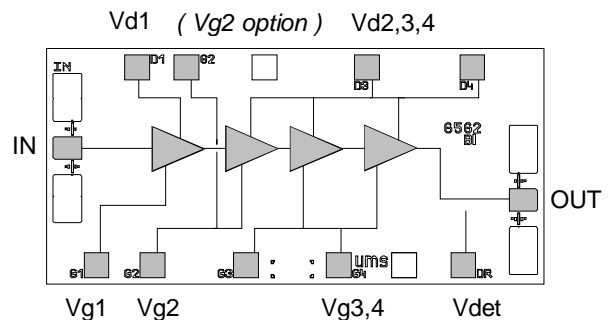
A B.I.T. (Build In Test) monitors a DC voltage that is representative of the microwave output power.

The circuit is manufactured with a PM-HEMT process, 0.25 μ m gate length, via holes through the substrate, air bridges and electron beam gate lithography.

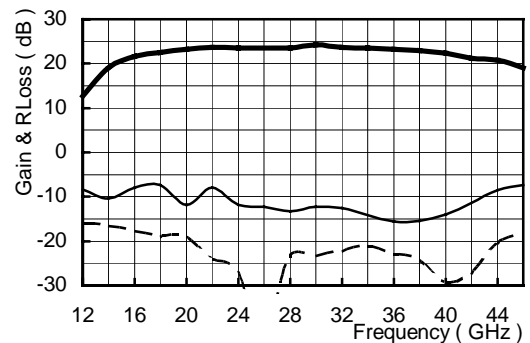
It is available in chip form.

Main Features

- Broadband performances : 20-40GHz
- 20dBm output power.
- 22dB \pm 1.0dB gain
- Very good broadband input matching
- On chip output power level DC detector
- Low DC power consumption, 300mA @ 3.5V
- Chip size : 0.88 X 1.72 X 0.10 mm



Typical on wafer measurements :



Input RLoss : dash line & output RLoss : solid line.

Main Characteristics

Tamb. = 25°C

Symbol	Parameter	Min	Typ	Max	Unit
Fop	Operating frequency range	20		40	GHz
G	Small signal gain	18	20		dB
P03	Output power at 3dB gain compression	20	23		dBm
Id	Bias current		300	400	mA

ESD Protection : Electrostatic discharge sensitive device. Observe handling precautions !

Electrical Characteristics for Broadband OperationT_{amb} = +25°C, V_{d1,2,3,4} = 3.5V

Symbol	Parameter	Min	Typ	Max	Unit
Fop	Operating frequency range (1)	20		40	GHz
G	Small signal gain [in 20GHz to 35GHz](1)	20	22		dB
G	Small signal gain (1)	18	20		dB
ΔG	Small signal gain flatness (1)		±1.0		dB
I _s	Reverse isolation (1)		50		dB
P1dB	Pulsed output power at 1dB compression (1)	18	20		dBm
P03	Output power at 3dB gain compression	20	23		dBm
IP3	3 rd order intercept point		29		dBm
PAE	Power added efficiency at saturation		10		%
VSWR _{in}	Input VSWR (1)			2.0:1	
VSWR _{out}	Output VSWR (1)			3.0:1	
NF	Noise figure (2)			10.0	dB
V _{det}	Detected voltage : at 25GHz@P _{out} =20dBm Detected voltage : at 38GHz@P _{out} =20dBm		0.8 0.4		V V
I _d	Bias current (2)		300	400	mA

(1) These values are representative for pulsed on-wafer measurements that are made without bonding wires at the RF ports. In the case of a jig or a module CW mode operation, the typical output power may be around 2dB less.

(2) Input matching is below 2:1 down to 10GHz.

(3) Voltage across an external 10kOhm parallel resistor connected to the voltage detector pad.

Absolute Maximum RatingsT_{amb} = 25°C (1)

Symbol	Parameter	Values	Unit
V _d	Drain bias voltage	5.0	V
I _d	Drain bias current	500	mA
V _g	Gate bias voltage	-2.0 to +0.4	V
P _{in}	Maximum peak input power overdrive (2)	+15	dBm
T _a	Operating temperature range	-40 to +85	°C

Tstg	Storage temperature range	-55 to +155	°C
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- (1) Operation of this device above anyone of these parameters may cause permanent damage.
(2) Duration < 1s.

Typical Scattering Parameters (On wafer S_{ij} measurements)Bias Conditions : $V_{d1,2,3,4} = 3.5$ Volt, $V_{g1,2,3,4} = -0.15$ Volt, $I_d = 300$ mA.

Freq. GHz	S11 dB	S11 /°	S12 dB	S12 /°	S21 dB	S21 /°	S22 dB	S22 /°
10.0	-13.3	138.0	-70.1	178.4	1.6	174.0	-5.8	-177.2
11.0	-14.0	137.0	-72.1	95.4	6.6	143.7	-7.3	178.0
12.0	-14.5	137.3	-64.2	-174.5	10.9	111.5	-8.3	174.0
13.0	-14.8	136.5	-68.9	123.0	15.1	74.6	-10.6	179.4
14.0	-15.1	133.5	-66.4	179.8	17.7	36.1	-9.9	-169.8
15.0	-15.8	132.9	-66.5	164.5	19.5	-1.4	-8.6	-172.9
16.0	-16.2	129.0	-63.8	-167.5	20.8	-38.1	-7.8	-173.7
17.0	-17.5	129.6	-61.0	161.9	21.2	-72.1	-6.9	173.7
18.0	-17.8	131.1	-61.5	150.7	21.8	-99.9	-7.3	164.6
19.0	-18.5	130.0	-57.6	132.3	21.9	-128.2	-7.5	155.8
20.0	-18.3	129.4	-63.4	122.7	23.2	-158.0	-10.8	149.5
21.0	-20.6	120.6	-57.2	116.0	22.4	172.2	-10.1	158.7
22.0	-22.9	139.6	-58.2	88.2	20.5	156.3	-7.4	141.8
23.0	-20.7	124.5	-51.6	48.4	22.0	144.4	-10.8	150.4
24.0	-25.1	133.7	-60.8	-167.2	23.2	106.2	-11.1	137.6
25.0	-26.1	129.3	-56.2	127.5	23.0	84.6	-12.2	145.2
26.0	-32.0	153.8	-55.3	96.6	22.9	62.8	-11.7	141.2
27.0	-28.8	-160.2	-60.8	92.0	22.9	41.8	-12.9	138.4
28.0	-25.1	-144.0	-57.2	103.2	23.1	19.9	-12.9	145.7
29.0	-22.7	-160.1	-55.7	90.9	22.7	-2.2	-11.7	145.2
30.0	-22.5	-154.6	-54.0	67.8	23.2	-18.7	-11.9	131.7
31.0	-20.9	-157.3	-58.2	68.9	23.3	-44.2	-13.6	127.7
32.0	-21.5	-160.9	-55.0	81.0	23.2	-64.6	-12.5	131.9
33.0	-20.2	-154.2	-52.7	58.7	23.1	-87.4	-12.9	111.7
34.0	-20.1	-160.0	-56.7	15.6	23.0	-107.2	-15.1	109.2
35.0	-19.7	-158.3	-57.8	56.8	22.9	-128.5	-16.3	102.4
36.0	-19.8	-163.5	-59.1	21.2	22.9	-147.9	-17.3	101.7
37.0	-19.6	-163.8	-60.2	60.7	22.9	-170.1	-17.6	85.3
38.0	-19.2	-162.4	-55.6	5.7	22.9	168.1	-19.1	61.2
39.0	-20.2	-173.2	-63.6	124.8	22.6	146.9	-20.9	40.0
40.0	-21.8	-176.4	-57.3	78.2	22.5	124.0	-19.4	12.3
41.0	-23.7	-173.2	-62.6	14.9	21.8	102.3	-17.7	-18.5
42.0	-26.1	-167.2	-60.1	92.4	21.7	78.6	-15.2	-39.3
43.0	-31.2	-138.4	-51.8	70.1	21.6	57.9	-12.7	-55.8
44.0	-27.3	-85.2	-54.2	56.5	21.5	34.7	-10.5	-69.3
45.0	-21.5	-92.9	-49.2	87.0	21.3	9.1	-8.3	-86.4
46.0	-26.2	-35.3	-46.5	-6.7	20.3	-16.3	-7.9	-101.5
47.0	-17.0	-27.4	-43.9	-55.8	20.1	-40.2	-7.8	-106.3
48.0	-11.6	-54.0	-39.1	-165.6	19.7	-67.5	-6.1	-111.4
49.0	-8.4	-55.8	-54.2	-160.8	18.9	-97.3	-4.9	-119.1
50.0	-5.7	-69.7	-44.5	-145.5	17.5	-129.8	-4.0	-126.7

Ref. : DSCHA30937290

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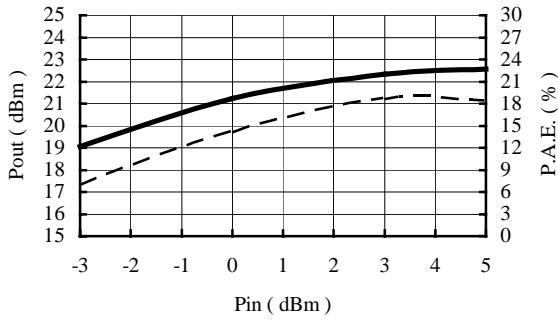
Specifications subject to change without notice

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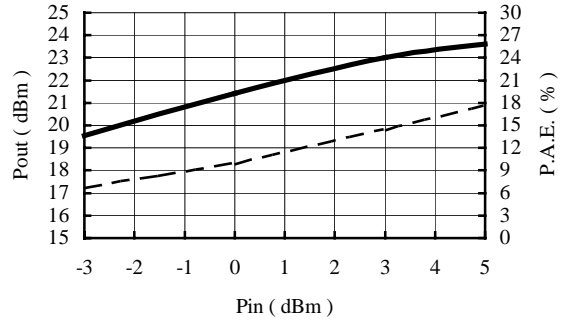
Typical On wafer Power Measurements

Bias Conditions : $V_{d1,2,3,4} = 3.5$ Volt, $V_{g1,2,3,4} = -0.15$ Volt, $I_d = 300$ mA.

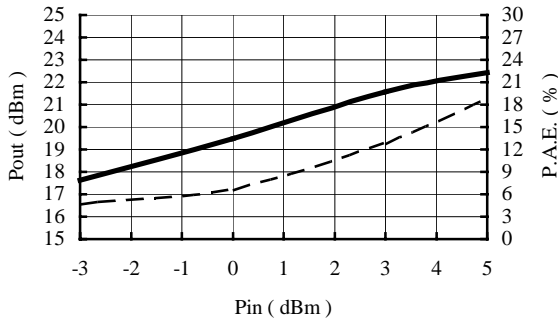
On wafer Pin / Pout at 20 GHz



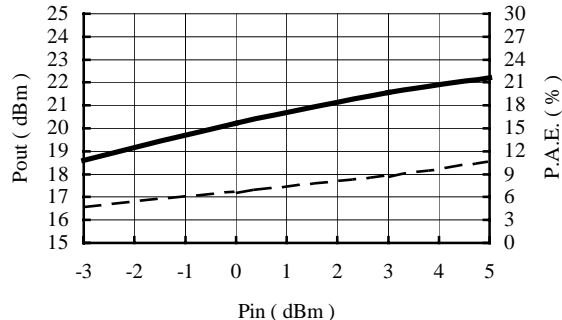
On wafer Pin / Pout at 28 GHz



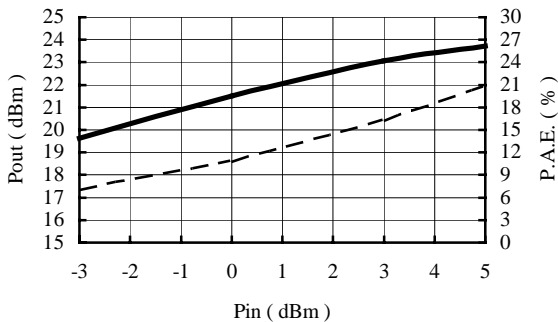
On wafer Pin / Pout at 22 GHz



On wafer Pin / Pout at 38 GHz



On wafer Pin / Pout at 26 GHz

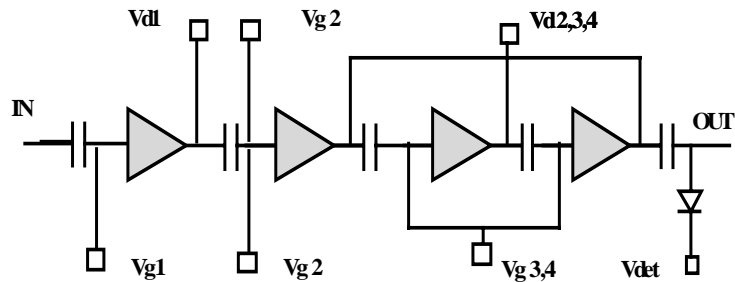


Notes :

- 1- Test conditions :
 $V_{d1,2,3,4} = 3.5$ Volt, $V_{g1,2,3,4} = -0.15$ Volt.
- 2- Power measurements are typical (solid lines). P.A.E. is representative of on wafer measurements on a typical circuit (Dotted lines).

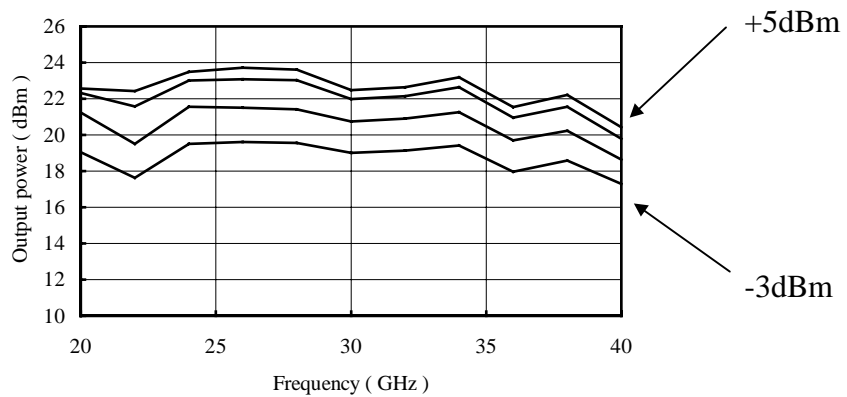
Typical Bias Tuning

The circuit schematic is given below :

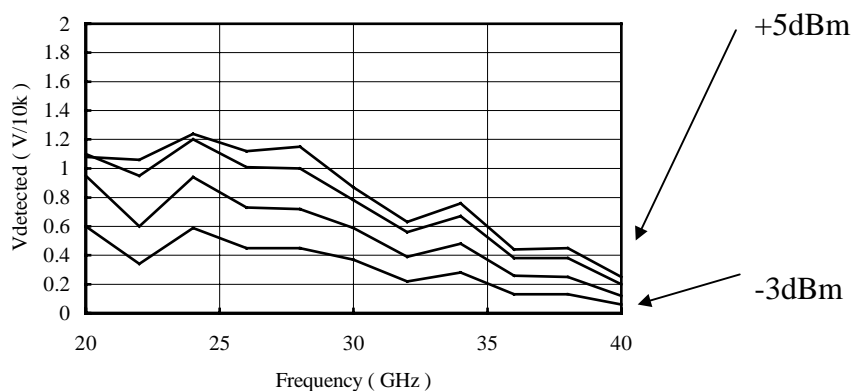


For medium power operation, the four drain biases are connected altogether. In a same way, all the gate biases are connected together at the same power supply, tuned to drive a small signal operating current of 300mA. A separate access to the gate voltages of the two first stages (Vg1,2) is provided in order to be able to tune the first stages for the application, as a lower noise amplifier or a multiplier. An additional pad is provided for monitoring the output power, using the Build In Test. This access, when connected to an external resistor of 10 kOhm (typical value) provides a DC voltage which follows the output power level.

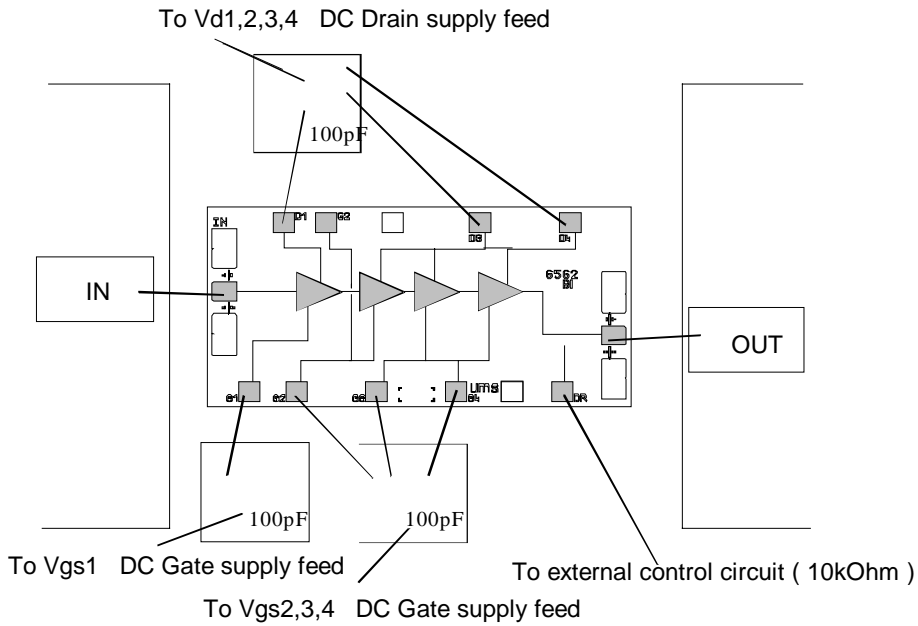
On wafer power measurements for fixed input power of -3dBm, 0 dBm +3dBm & +5 dBm.



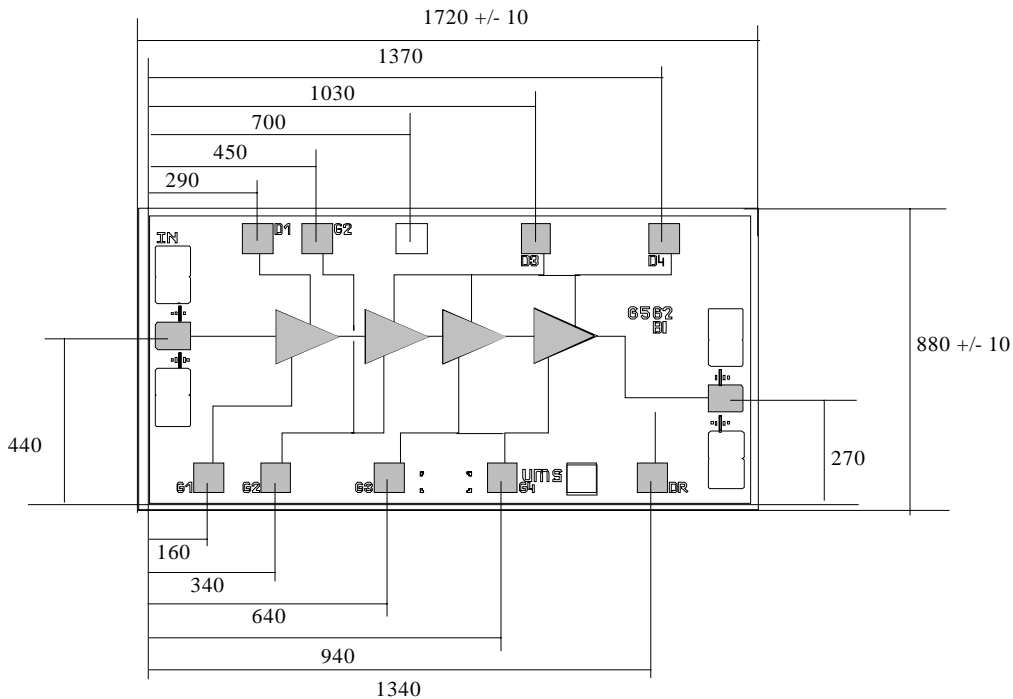
On wafer detected voltage for fixed input power of -3dBm, 0 dBm +3dBm & +5 dBm.



Chip Assembly and Mechanical Data



Note : Supply feed should be capacitively bypassed. 25µm diameter gold wire is recommended.



Bonding pad positions.
 (Chip thickness : 100µm. All dimensions are in micrometers)

Ordering Information

Chip form : CHA3093a99F/00

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